Notice of References Cited

Application/Control No. 10/657,616		Applicant(s)/Patent Under Reexamination LEE ET AL.	
Examiner	Art Unit		
Laura M. Schillinger	2813	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0032340 A1	02-2005	Takizawa, Teruo	438/489
*	В	US-2005/0023576 A1	02-2005	Lee et al.	257/288
*	С	US-2004/0235264 A1	11-2004	Forbes, Leonard	438/429
*	D	US-2004/0232422 A1	11-2004	Forbes, Leonard	257/063
*	E	US-2004/0221792 A1	11-2004	Forbes, Leonard	117/004
*	F	US-2002/0125475 A1	09-2002	Chu et al.	257/55
*	G	US-2002/0090772 A1	07-2002	Higashi, Seiichiro	438/166
*	Н	US-6,876,010 B1	04-2005	Fitzgerald, Eugene A.	257/191
*	1	US-6,858,502 B2	02-2005	Chu et al.	438/285
*	J	US-5,256,550 A	10-1993	Laderman et al.	438/509
*	К	US-4,927,471 A	05-1990	Okuda, Hiroshi	148/33.5
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
·	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.